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**INFORMATION
DISCLOSURE STATEMENT
TRANSMITTAL**

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

<i>Application Number</i>	
<i>Filing Date</i>	
<i>First Named Inventor</i>	DE CLERCQ, MARK N., O.
<i>Group Art Unit</i>	
<i>Examiner Name</i>	
<i>Atty. Docket Number</i>	NL04 0156 US1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number No.-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
	1	US- 2003/132777	07/17/2003	LAACKMANN PETER ET AL.	
	2	US- 2003/218475	11/27/2003	GAMMEL BERNDT	
	3	US- 5 861 652	01/19/1999	COLE ET AL.	
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number (ctry ³ -no. ⁴ -kind ⁵ , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
	1	I. RAYANE ET AL: "A DIGITAL BIST FOR OPERATIONAL AMPLIFIERS EMBEDDED IN MIXED-SIGNAL CIRCUITS"; PROCEEDINGS OF IEEE VLSI TEST SYMPOSIUM; 1999 PP 304-310.	
	2	KHALKHAL A ET AL: "ON-CHIP MEASUREMENT OF INTERCONNECT CAPACITANCES IN A CMOS PROCESS"; PROCEEDINGS OF THE INTERNATIONAL CONF. ON MICROELECTRONIC TEST STRUCTURES NARA JP; MAR 22-25 1995; N.Y. IEEE US; 22 MAR 1995; PP 145-149	

Examiner Signature	Date Considered
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.